

50A 650V Trench Fieldstop IGBT with anti-parallel diode SRE50N065FSGS8
General Description

The SRE50N065FSGS8 is a Field Stop Trench IGBT with anti-parallel diode, which offers ultra-low switching losses, high energy efficiency for switching applications such as PFC Power Supply, Inverter, etc.

The SRE50N065FSGS8 package is TO-247.

Features

- High Breakdown Voltage to 650V
- Advanced Trench Fieldstop Technology
 - Ultra low E_{off}
 - High Ruggedness, Temperature Stability
 - Easy Parallel Switching Capability due to Positive Temperature Coefficient in $V_{CE(SAT)}$
- Non-automotive Qualified
- Enhanced Avalanche Capability

Application

- Inverter
- Uninterruptible power supplies
- PFC application
- Converter with high switching frequency

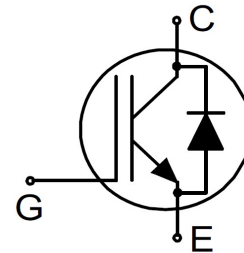
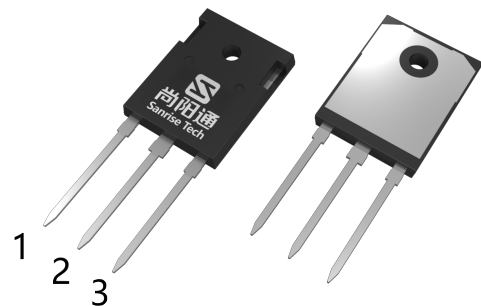
Symbol


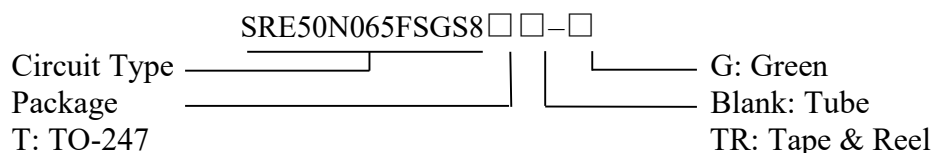
Figure 1 Symbol of SRE50N065FSGS8

Package Type


TO-247

- Pin 1- gate
- Pin 2&backside-collector
- Pin 3-emitter

Figure 2 Package Type of SRE50N065FSGS8

Ordering Information


Package	Part Number	Marking ID	Packing Type
TO-247	SRE50N065FSGS8T-G2	SRE50N065FSGS8TG2	Tube

Absolute Maximum Ratings

Parameter		Symbol	Rating	Unit
Collector-emitter Voltage		V_{CES}	650	V
Gate-emitter Voltage		V_{GES}	± 20	V
Transient Gate-emitter Voltage			± 30	V
Continuous Collector Current	$T_C=25^\circ\text{C}$	I_C	90	A
	$T_C=120^\circ\text{C}$		50	
Pulsed Collector Current, Limited by T_{Jmax}		I_{CM}	200	A
Diode Continuous Collector Current	$T_C=25^\circ\text{C}$	I_F	50	A
	$T_C=100^\circ\text{C}$		32	
Diode Pulsed Current, Limited by T_{Jmax}		I_{FM}	150	A
Power Dissipation	$T_C=25^\circ\text{C}$	P_{tot}	326	W
	$T_C=100^\circ\text{C}$		163	
Operating Junction Temperature Range		T_J	-40 ~ 175	$^\circ\text{C}$
Storage Temperature Range		T_{STG}	-55 ~ 150	$^\circ\text{C}$
Lead Temperature (Soldering, 10 sec)		T_{LEAD}	260	$^\circ\text{C}$

Thermal Resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
IGBT Thermal Resistance, Junction-to-Case	R_{thJC}	-	-	0.46	$^\circ\text{C}/\text{W}$
Diode Thermal Resistance, Junction-to-Case	R_{thJC}	-	-	1.10	
Thermal Resistance, Junction-to-Ambient	R_{thJA}	-	-	40	

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Electrical Characteristics
 $T_J = 25^\circ\text{C}$, unless otherwise specified.

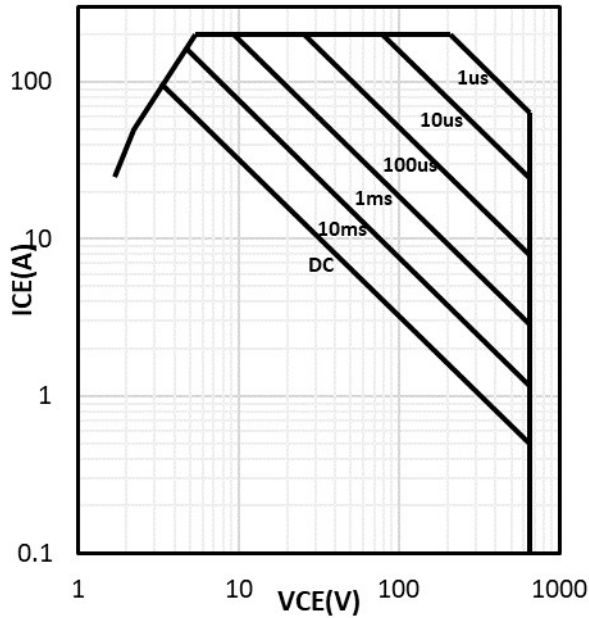
Parameter		Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Statistic Characteristics							
Collector-emitter Voltage	Breakdown	BV_{CES}	$V_{GE}=0V, I_C=250\mu A$	650			V
Gate Threshold Voltage		$V_{GE(th)}$	$V_{CE}=V_{GE}, I_C=250\mu A$	3.8	4.5	5.3	V
Collector-emitter saturation voltage		V_{CEsat}	$V_{GE}=15V, I_C=50A,$ $T_J=25^\circ\text{C}$		1.58	2.00	V
			$T_J=125^\circ\text{C}$		2.05		V
			$T_J=175^\circ\text{C}$		2.23		V
Zero Gate Voltage Collector Current		I_{CES}	$V_{CE}=650V, V_{GE}=0V$ $T_J=25^\circ\text{C}$		0.1	40	μA
			$T_J=175^\circ\text{C}$			1	mA
Gate-emitter Leakage Current	Forward	I_{GESF}	$V_{GE}=20V, V_{CE}=0V$			100	nA
	Reverse	I_{GESR}	$V_{GE}=-20V, V_{CE}=0V$			-100	nA
Dynamic Characteristics							
Input Capacitance		C_{IES}	$V_{CE}=25V, V_{GE}=0V,$ $f=100\text{ KHz}$		2480		pF
Output Capacitance		C_{OES}			392		
Reverse Transfer Capacitance		C_{RES}			21		
Gate Resistance		R_G	$f=1\text{ MHz, Open Drain}$		1.7		Ω
Turn-on Delay Time		$t_{d(on)}$	$T_J=25^\circ\text{C}$ $V_{CC}=400V, I_C=25A$ $R_G=10\Omega, V_{GE}=0/15V$ Energy losses include "tail" and diode reverse recovery		18		ns
Rise Time		t_r			15		ns
Turn-off Delay Time		$t_{d(off)}$			126		ns
Fall Time		t_f			17		ns
Turn-on energy		E_{on}			0.46		mJ
Turn-off energy		E_{off}			0.16		mJ
Total switching energy		E_{ts}			0.62		mJ
Turn-on Delay Time		$t_{d(on)}$			20		ns
Rise Time		t_r			31		ns
Turn-off Delay Time		$t_{d(off)}$			117		ns
Fall Time		t_f		33		ns	
Turn-on energy		E_{on}		1.12		mJ	
Turn-off energy		E_{off}		0.51		mJ	
Total switching energy		E_{ts}		1.63		mJ	
Gate to Emitter Charge		Q_{GE}	$V_{CC}=400V, I_C=50A$ $V_{GE}=0\text{ to }15V$		21		nC
Gate to Collector Charge		Q_{GC}			47		
Gate Charge Total		Q_G			115		

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Parameter	Symbol	Test Conditions	Min.	Typ.	Max	Unit
Reverse Diode Characteristics						
Diode Forward Voltage	V_F	$I_F=25A$ $T_J=25^{\circ}C$		1.32	1.55	V
		$I_F=25A$ $T_J=125^{\circ}C$		1.42		
		$I_F=25A$ $T_J=175^{\circ}C$		1.52		
		$I_F=50A$ $T_J=25^{\circ}C$		1.70	2.0	
		$I_F=50A$ $T_J=125^{\circ}C$		2.00		
		$I_F=50A$ $T_J=175^{\circ}C$		2.34		
Diode Reverse Recovery Time	Q_{rr}	$T_J=25^{\circ}C$ $V_R=400V, I_F=50A$ $dI_F/dt=1000A/\mu s$		0.033		μC

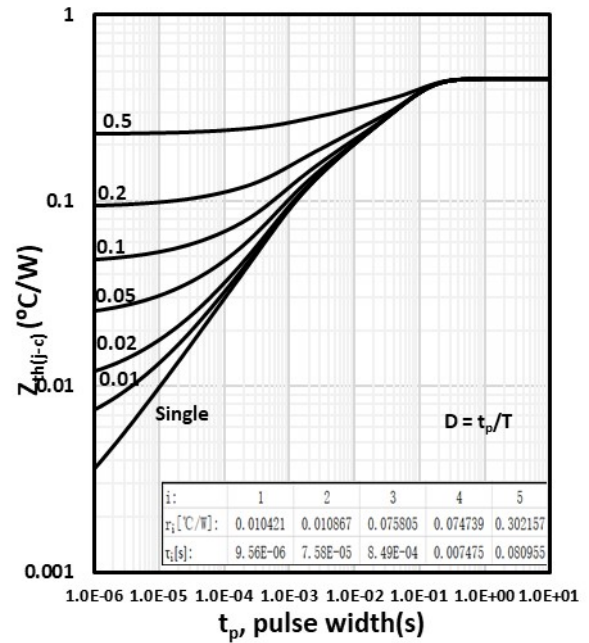
Typical Performance Characteristics

Figure 3: IGBT FBSOA



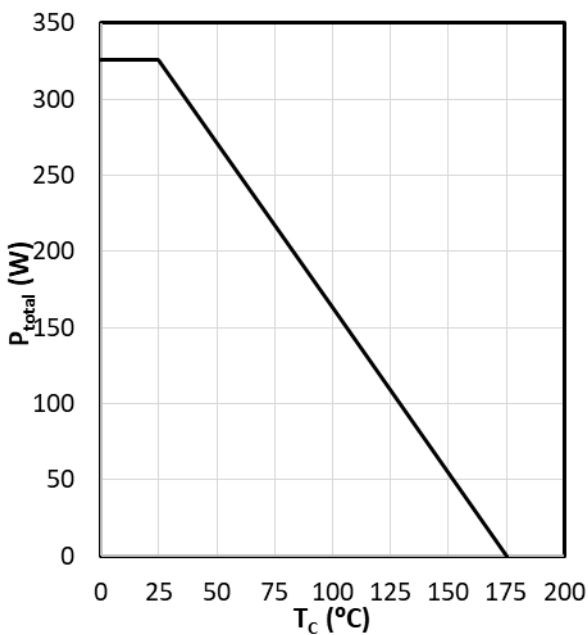
$$I_C = f(V_{CE}); V_{GE} \geq 15/0V; T_j \leq 175^\circ\text{C}$$

Figure 4: IGBT transient thermal impedance



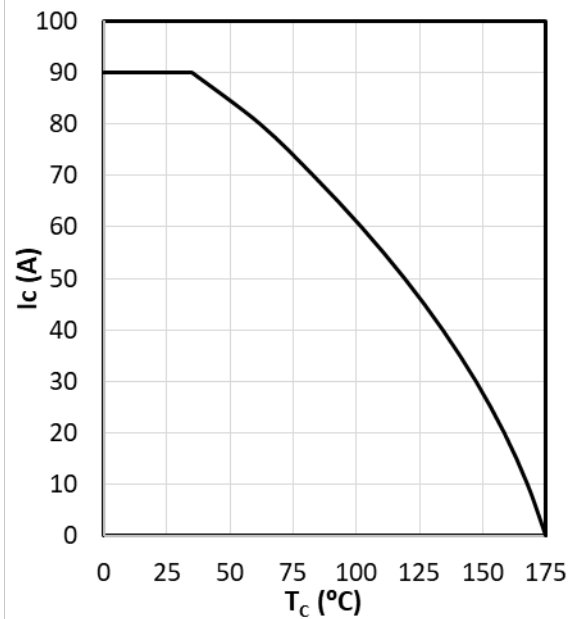
$$R_{th(j-c)} = f(t_p); \text{duty cycle: } D = t_p/T$$

Figure 5: Power dissipation



$$P_{tot} = f(T_c);$$

Figure 6: Collector current vs. temperature



$$I_c = f(T_c); V_{GE} \geq 15V; T_j \leq 175^\circ\text{C}$$

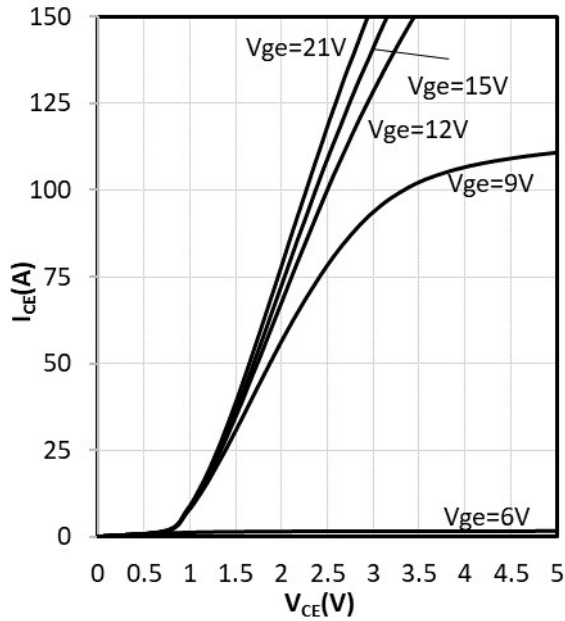
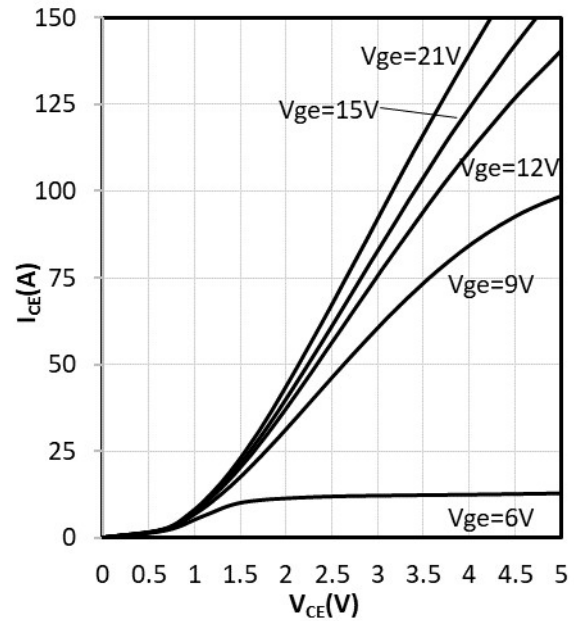
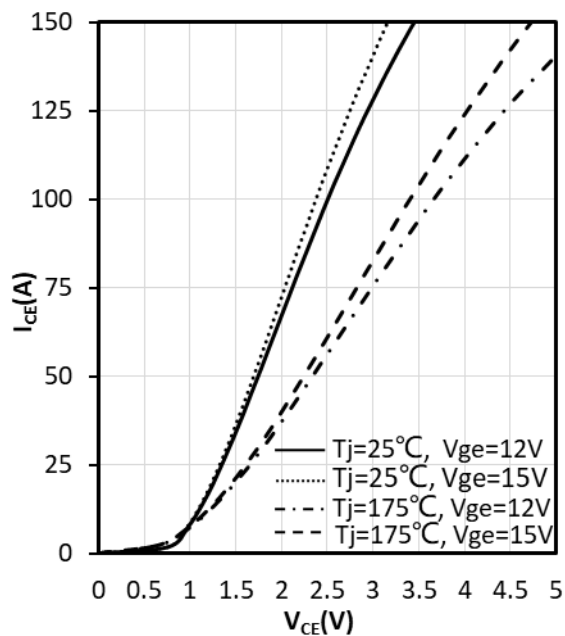
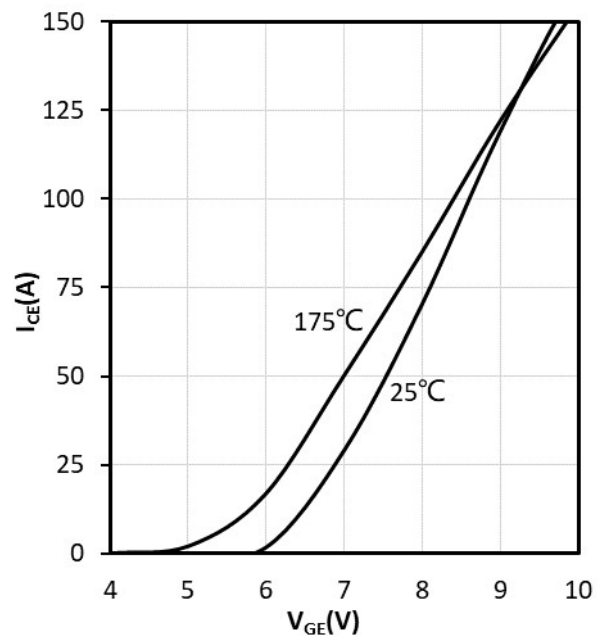
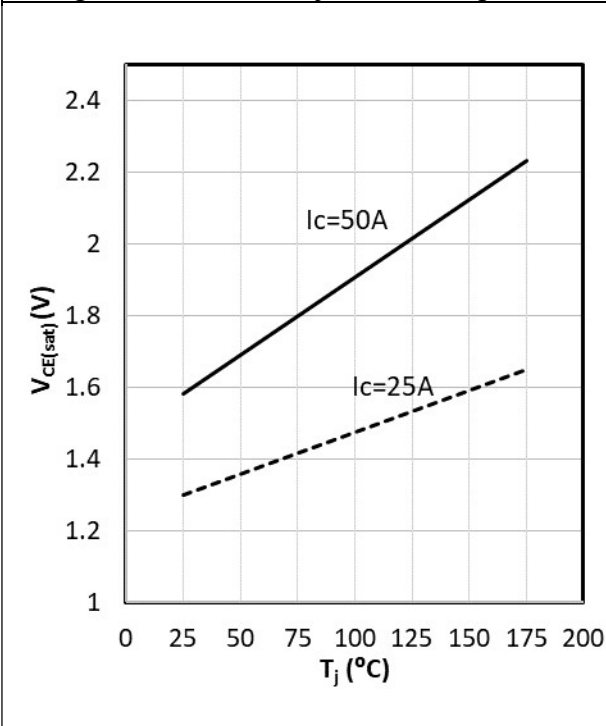
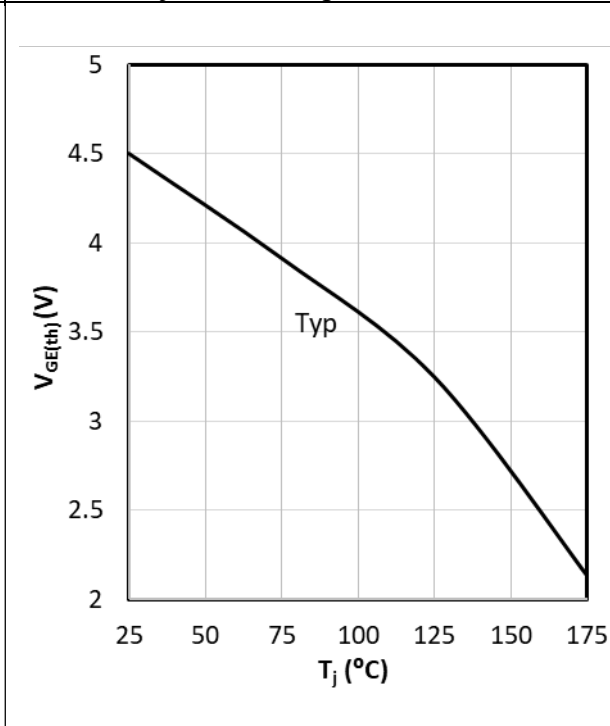
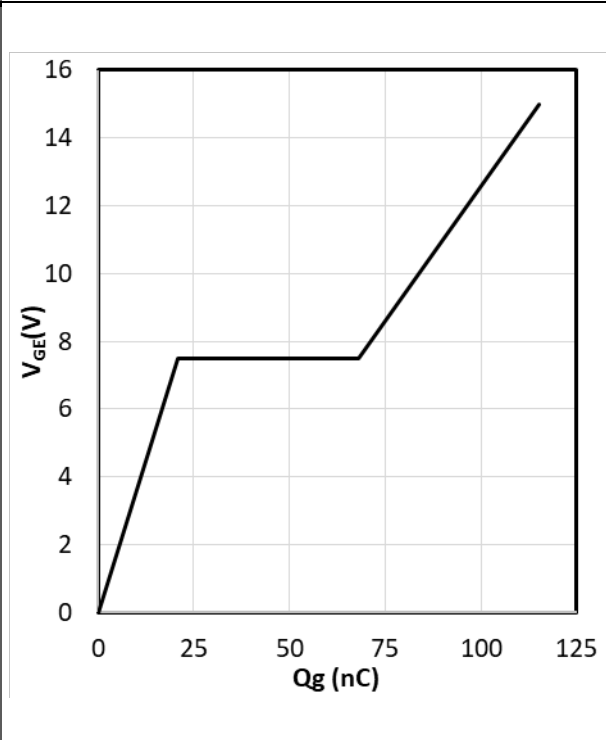
Figure 7: Typical Output Characteristics

 $I_C = f(V_{CE}); T_j = 25^\circ\text{C}; \text{parameter: } V_{GE}$
Figure 8: Typical Output Characteristics

 $I_C = f(V_{CE}); T_j = 175^\circ\text{C}; \text{parameter: } V_{GE}$
Figure 9: Typical Output Characteristics

 $I_C = f(V_{CE}); \text{parameter: } V_{GE}$
Figure 10: Typical transfer characteristic

 $I_C = f(V_{CE}); T_j = 25^\circ\text{C vs } 175^\circ\text{C}$

Figure 11: Typical collector-emitter saturation voltage as a function of junction temperature


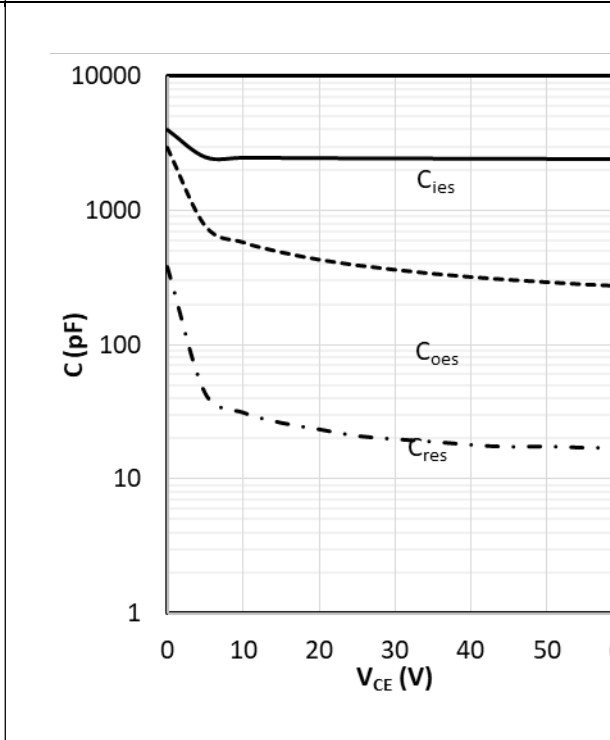
$V_{CE} = f(T_j); V_{GE} = 15V$

Figure 12: Gate-emitter threshold voltage as a function of junction temperature


$V_{GE} = f(T_j); I_{CE} = 250\mu A$

Figure 13: Typical Gate Charge


$V_{GE} = f(Q_{gate}); I_c = 50A$

Figure 14: Typical Capacitances


$C = f(V_{CE}); V_{GE} = 0; f = 100\text{ KHz}$

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Figure 15: Typical switching energy losses as a function of collector current

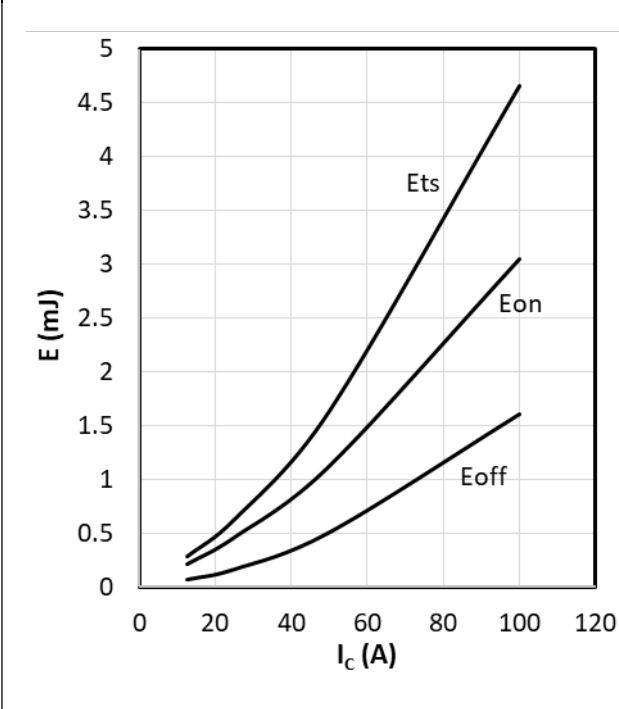

 $E=f(I_c)$; $V_{CE}=400V$; $T_j=25^\circ C$; $R_G=10\Omega$

Figure 16: Diode transient thermal impedance

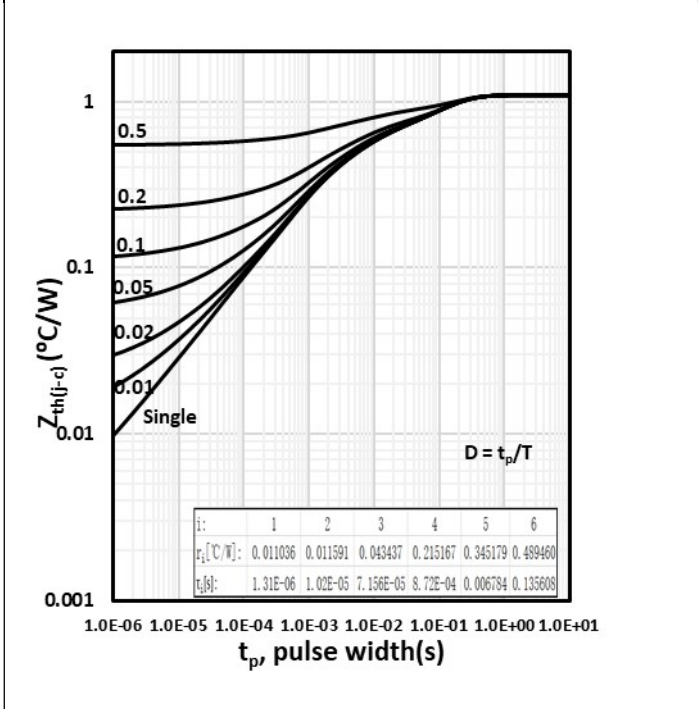
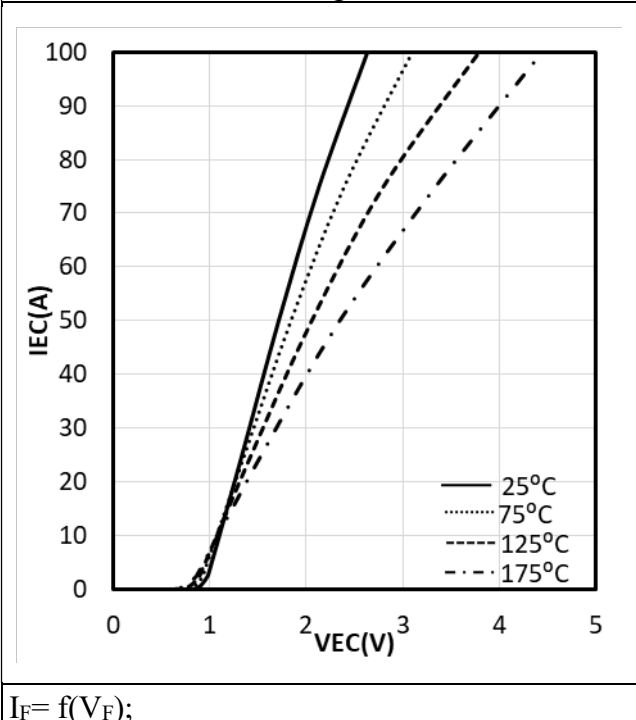
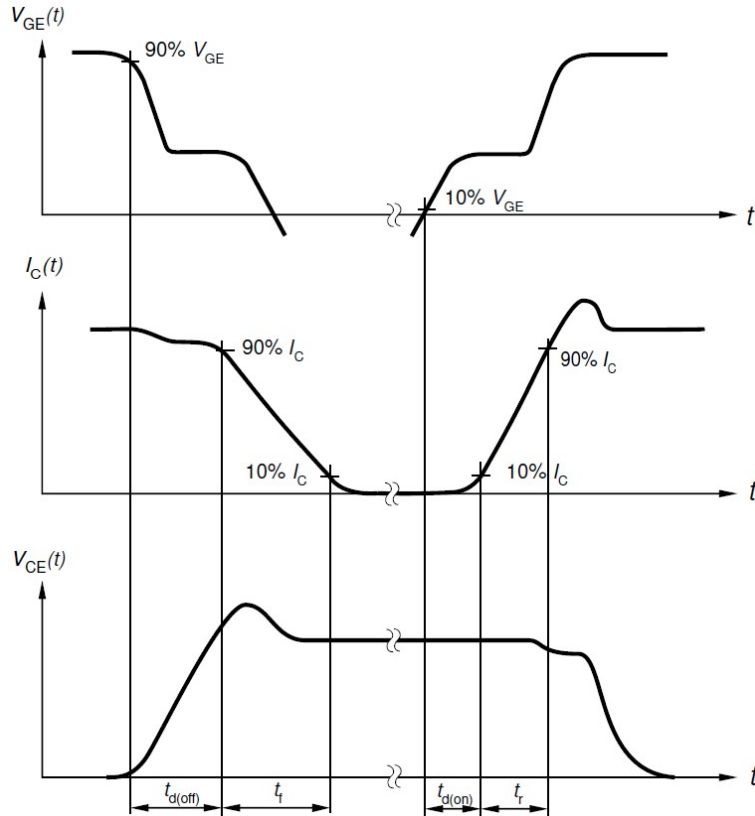

 $R_{th(j-c)}=f(t_p)$; duty cycle: $D= t_p/T$

Figure 17: Typical diode forward current as a function of forward voltage

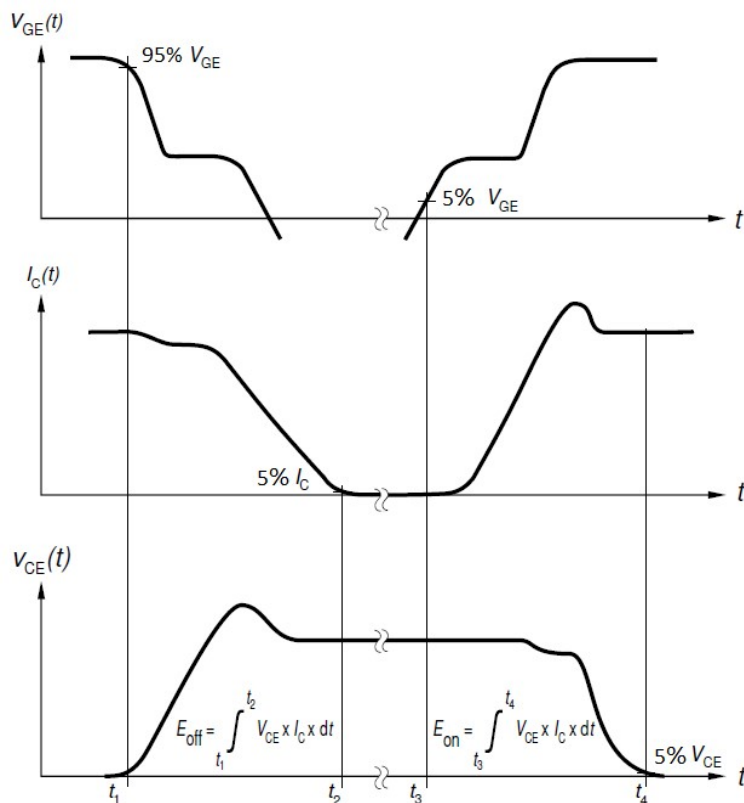

 $I_F=f(V_{FE})$;

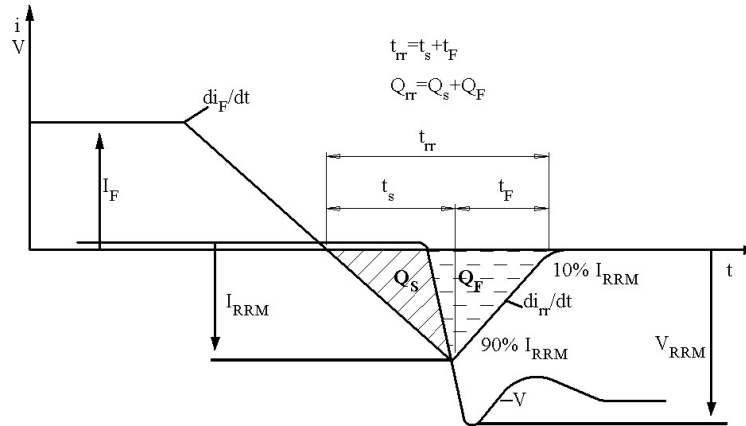
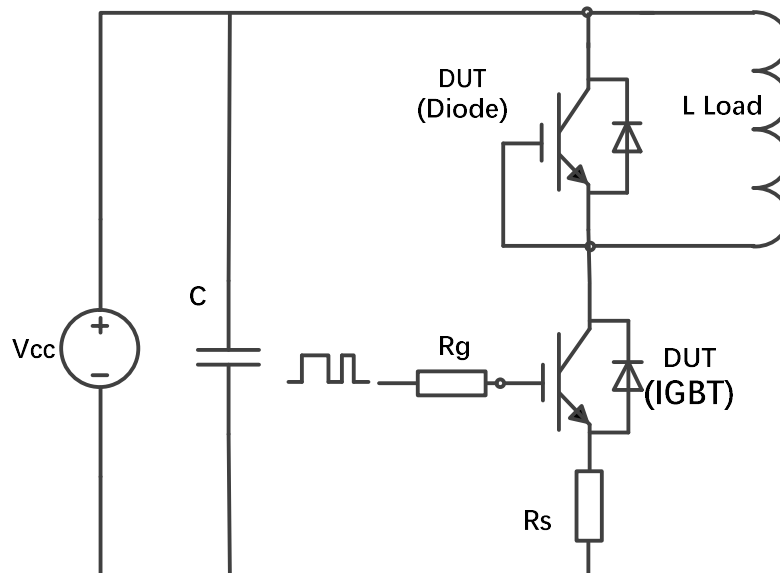
Test Circuits

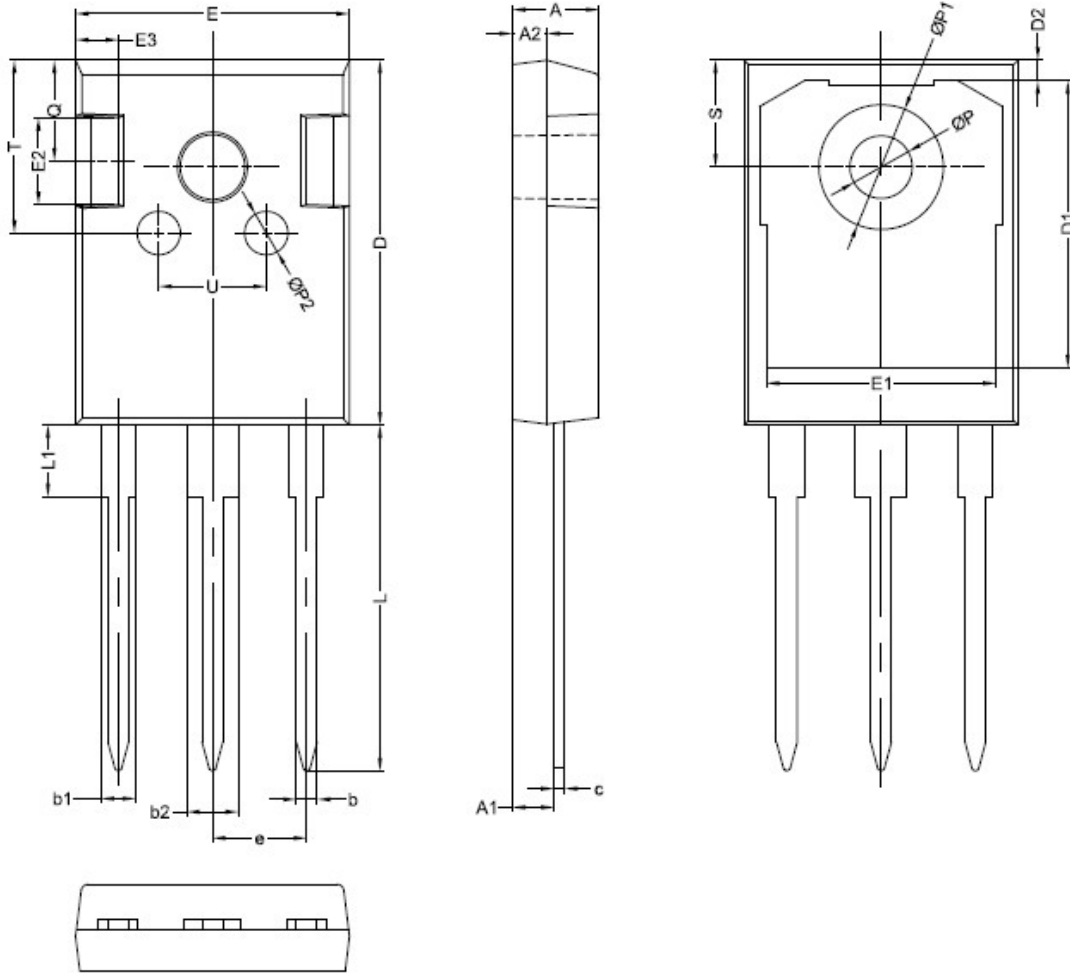
1. Definition Switching times



2. Definition Switching losses



3. Definition Diode Switching Characteristics

3. Dynamic test circuit


Mechanical Dimensions
TO-247
Unit: mm


Symbol	Dimensions(mm)			Symbol	Dimensions(mm)		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.80	5.00	5.20	E2	-	5.00	-
A1	2.21	2.41	2.61	E3	-	2.50	-
A2	1.90	2.00	2.10	e	5.44(BSC)		
b	1.10	1.20	1.35	L	19.42	19.92	20.42
b1	-	2.00	-	L1	-	4.13	-
b2	-	3.00	-	P	3.50	3.60	3.70
c	0.55	0.60	0.75	P1	-	-	7.40
D	20.80	21.00	21.20	P2	-	2.50	-
D1	-	16.55	-	Q	-	5.80	-
D2	-	1.20	-	S	6.05	6.15	6.25
E	15.60	15.80	16.00	T	-	10.00	-
E1	-	13.30	-	U	-	6.20	-



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Main Site:

- Headquarter

Shenzhen Sanrise Technology Co., LTD.
A1206, Skyworth building, No. 008, gaoxinnan 1st Road,
Gaoxin District, Yuehai street, Nanshan District, ShenZhen,
P.R. China

Tel: +86-755-22953335

Fax: +86-755-22916878

- Shanghai Office

Sanrise Technology Limited Company
Rm.401, Building B, No. 666, Zhangheng Road,
Zhangjiang Hi-Tech Park, Shanghai, P.R.China

Tel: +86-21-68825918